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PATENT NUMBER

PTO-2040 12/99

U.S. UTILITY Patent Application

OLP.E. PATENT DATE

APPLICATION NO. 09/620021 D CLASS SUBCLASS ART UNIT EXAMINER 1/4 S81 2133

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729 WII

Continuous application and decompression of test patterns to a circuit-under-test $% \left(1\right) =\left(1\right) +\left(1\right) +$

Drwg.	DRAWINGS Figs. Drwg.	Print Fig.	Total Claims		
		Print Fig.		Print Claim for O.G	
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